

<b>Notice of References Cited</b>	Application/Control No. 10/561,830	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0110085	06-2004	Iwai et al.	430/270.1
*	B	US-2004/0029037	02-2004	Kamabuchi et al.	430/270.1
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	M	US-			

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**NON-PATENT DOCUMENTS**

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